TENTATIVE

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC7WH245FU

(UNDER DEVELOPMENT)

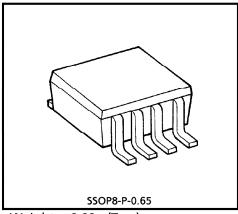
DUAL BUS TRANSCEIVER

The TC7WH245FU is an advanced high speed CMOS DUAL BUS TRANSCEIVER fabricated with silicon gate CMOS technology. It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

It is intended for two-way asynchronous communication between data busses. The direction of data transmission is determined by the level of the DIR input.

The enable input $\overline{(G)}$ can be used to disable the device so that the busses are effectively isolated.

All inputs are equipped with protection circuits against static discharge.



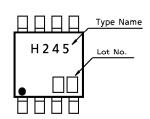
Weight: 0.02g (Typ.)

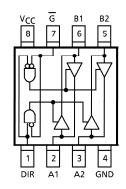
FEATURES

- High Speed t_{pd} = 4.0ns (Typ.) at V_{CC} = 5V
- Low Power Dissipation İ_{CC} = 4μA (Max.) at Ta = 25°C
- High Noise Immunity VNIH = VNIL = 28% VCC (Min.)
- Balanced Propagation Delays ····· t_{pLH}=t_{pHL}
- Wide Operating Voltage Range… V_{CC} (opr) = 2~5.5V
- Low Noise V_{OLP} = 0.8V (Max.)

MARKING

PIN ASSIGNMENT (TOP VIEW)





APPLICATION NOTES

- Do not apply a signal to any bus terminal when it is in the output mode. Damage may result.
- All floating (high impedance) bus terminals must have their input levels fixed by means of pull up or pull down resistors or bus terminator IC's such as the TOSHIBA TC40117BP.
- 3) A parasitic diode is formed between the bus and V_{CC} terminals. Therefore bus terminal can not be used to interface 5V to 3V systems directly.

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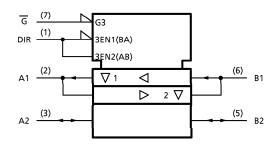
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MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage Range	V _{CC}	-0.5~7.0	V
DC Input Voltage	V _{IN}	-0.5~7.0	٧
DC Output Voltage	Vout	-0.5~V _{CC} +0.5	٧
Input Diode Current	ΙΚ	– 20	mA
Output Diode Current	lok	± 20	mA
DC Output Current	lout	± 25	mΑ
DC V _{CC} /Ground Current	lcc	± 50	mA
Power Dissipation	P _D	300	mW
Storage Temperature	T _{stg}	- 65∼150	°C
Lead Temperature (10 s)	TL	260	°C

LOGIC DIAGRAM



TRUTH TABLE

INPUTS		FUNC	OUTPUT	
G	DIR	A BUS	B BUS	OUTFUL
L	L	OUTPUT	INPUT	A = B
L	Η	INPUT	OUTPUT	B = A
Н	×	High im	Z	

x : Don't care Z : High impedance

RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Supply Voltage	Vcc	2.0~5.5	V	
Input Voltage	VIN	0~5.5	V	
Output Voltage	Vout	0~V _{CC}	V	
Operating Temperature	T _{opr}	- 40∼85	°C	
Input Pice and Fall Time	dt/dv	$0\sim100 \text{ (V}_{CC} = 3.3 \pm 0.3 \text{V)}$	ns/V	
Input Rise and Fall Time	at/av	$0\sim20 \ (V_{CC} = 5 \pm 0.5V)$		

DC ELECTRICAL CHARACTERISTICS

GUADA CTEDICTIC	CVMPOL TEST COMPLETE		ONDITION	Vac	Ta = 25°C			Ta = -4	LINUT	
CHARACTERISTIC	SYMBOL	L TEST CONDITION		V _C C (V)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High-Level				2.0	1.50	_		1.50	_	
Input Voltage	V _{IH}	V _{IH} —		3.0~ 5.5	V _C C ×0.7	_	_	V _C C ×0.7	_	V
Low-Level				2.0	_	_	0.50	_	0.50	
Input Voltage	VIL		_	3.0~ 5.5	_	_	V _C C × 0.3	_	V _{СС} ×0.3	V
				2.0	1.9	2.0	_	1.9	_	
High Lovel		VIN = VIH	$I_{OH} = -50\mu A$	3.0	2.9	3.0	_	2.9		V
High-Level Output Voltage	VOH			4.5	4.4	4.5	_	4.4	_	
Output Voltage			$I_{OH} = -4mA$	3.0	2.58	_	_	2.48	_	
			I _{OH} = -8mA	4.5	3.94	_	_	3.80	_	
	V _{OL}	V _{IN} = V _{IH}	I _{OL} = 50μA	2.0	_	0.0	0.1	_	0.1	
Low-Level				3.0		0.0	0.1	_	0.1	
Output Voltage				4.5	_	0.0	0.1	_	0.1	V
Cutput Voltage		OI VIL	$I_{OL} = 4mA$	3.0	_		0.36		0.44	
			$I_{OL} = 8mA$	4.5		1	0.36	_	0.44	
3-State Output Off-State Current	loz	V _{IN} = V _{IH} or V _{IL} V _{OUT} = V _{CC} or GND		5.5	_	_	± 0.25	_	± 2.5	μ A
Input Leakage Current	IIN	V _{IN} = 5.5V or GND		0~ 5.5	_	_	± 0.1	_	± 1.0	μ A
Quiescent Supply Current	lcc	V _{IN} = V _{CC} or GND		5.5	_	_	4.0	_	40.0	μΑ

AC	ELECTRICAL	CHARACTERISTICS	(Input t	$r = t_f = 3ns$
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CHADACTERISTIC	SYMBOL TEST CO		ONDITION		7	Ta = 25°C		Ta = -40~85°C		UNIT
CHARACTERISTIC	STIVIBUL		V _{CC} (V)	C _L (pF)	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
			3.3 ± 0.3	15		5.8	8.4	1.0	10.0	
Propagation Delay	tpLH		3.5 ± 0.5	50		8.3	11.9	1.0	13.5	nc
Time	tpHL		5.0 ± 0.5	15		4.0	5.5	1.0	6.5	ns
			3.0 ± 0.5	50		5.5	7.5	1.0	8.5	
			3.3 ± 0.3	15		8.5	13.2	1.0	15.5	
3-State Output Enable	^t pZL ^t pZH	$R_L = 1k\Omega$		50		11.0	16.7	1.0	19.0	nc
Time			5.0 ± 0.5	15	1	5.8	8.5	1.0	10.0	ns
			3.0 ± 0.3	50		7.3	10.6	1.0	12.0	
3-State Output	tpLZ	$R_L = 1k\Omega$	3.3 ± 0.3	50		11.5	15.8	1.0	18.0	200
Disable Time	t _{pHZ}	K = 1K22	5.0 ± 0.5	50		7.0	9.7	1.0	11.0	ns
Output to Output	tosLH	(Note 1)	3.3 ± 0.3	50	_	_	1.5	-	1.5	ns
Skew	tosHL		Note 1) 5.0 ± 0.5				1.0	_	1.0	ns
Input Capacitance	CIN	DIR, G				4	10	_	10	рF
Bus Input Capacitance	C _{I/O}	An, Bn				8	_	—	_	рF
Power Dissipation Capacitance	C _{PD}	(Note 2)				21	_		_	pF

(Note 1) : Parameter guaranteed by design. $t_{OSLH} = |t_{pLHm} - t_{pLHn}|$, $t_{OSHL} = |t_{pHLm} - t_{pHLn}|$ (Note 2) : C_{PD} is defined as the value of the internal equivalent capacitance which is

calculated from the operating current consumption without load.

Average operating current can be obtained by the equation :

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC} / 2$ (per bit)

NOISE CHARACTERISTICS (Ta = 25° C, Input $t_r = t_f = 3$ ns)

CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{CC} (V)	TYP.	IMIT	UNIT
Quiet Output Maximum Dynamic V _{OL}	V _{OLP}	C _L = 50pF	5.0	0.5	0.8	٧
Quiet Output Minimum Dynamic V _{OL}	V _{OLV}	C _L = 50pF	5.0	- 0.5	- 0.8	٧
Minimum High Level Dynamic Input Voltage	V _{IHD}	C _L = 50pF	5.0	_	3.5	V
Maximum Low Level Dynamic Input Voltage	V _{ILD}	C _L = 50pF	5.0	_	1.5	V

INPUT EQUIVALENT CIRCUIT

